



Contribution ID: 68

Type: **not specified**

Radiation hardness of GaAs: Cr and Si sensors irradiated by 20 MeV electron beam

Thursday, 25 January 2018 09:40 (20 minutes)

Presenter: KRUCHONAK, Uladzimir (Joint Institute for Nuclear Research (RU))

Session Classification: CLICdp Calorimetry R&D & Software and Detector Validation joint session